"Metal-active-layer TFT"

UAlg:FCT – INESC:MN

"Metal-active-layer TFT"

P. Stallinga J. Bastos

(23 July 2010)

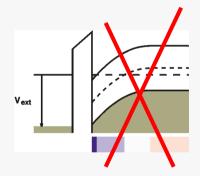


UAIg:FCT – INESC:MN Metal active layer TFT (Stallinga/Bastos) 23 July 2010

Why a TFT is not a MOS-FET

A TFT is made of a **thin** film and cannot accommodate band bendings.

A TFT normally works in **accumulation** and thus cannot store the immobile charge needed for band bendings (there are no electronic states, N_{D}^+).



There are no band bendings!

Not even in thick film transistors! Not even at contacts!

All bias-induced charge is free charge, adjacent to the interface



UAIg:FCT - INESC:MN Metal active layer TFT (Stallinga/Bastos) 23 July 2010

The Algarve Model

One single simple axiom:

Any charge induced by the gate is at the interface

The device is purely **two-dimensional**

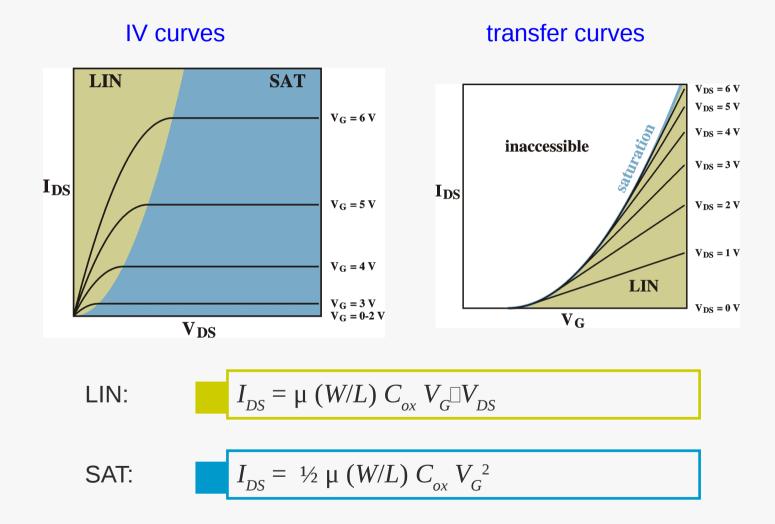
The device is a like a metal-plates capacitor

Q = C V

$$Q(x) = q p(x) = C_{ox}[V(x)-V_{g}]$$
$$I(x) = W q p(x) \mu [-dV(x)/dx]$$



The Algarve Model TFT curves



Organic TFTs behave like MOS-FETs



"If what you are saying is correct, we can use other materials as well for TFTs"

Yes! Since doping is not essential.

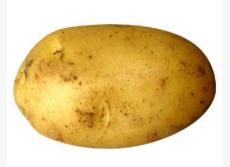
As long as the **mobility** of the charges is high enough

As long as the charges have a barrier going (leaking) to the gate

Any semiconductor will do. Wait, any material will do. Even a potato!

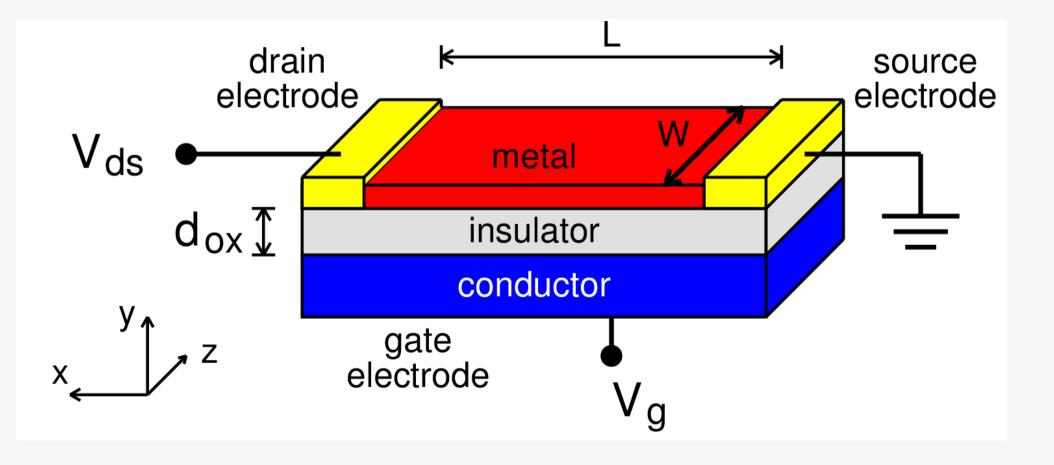
Even a metal will do!





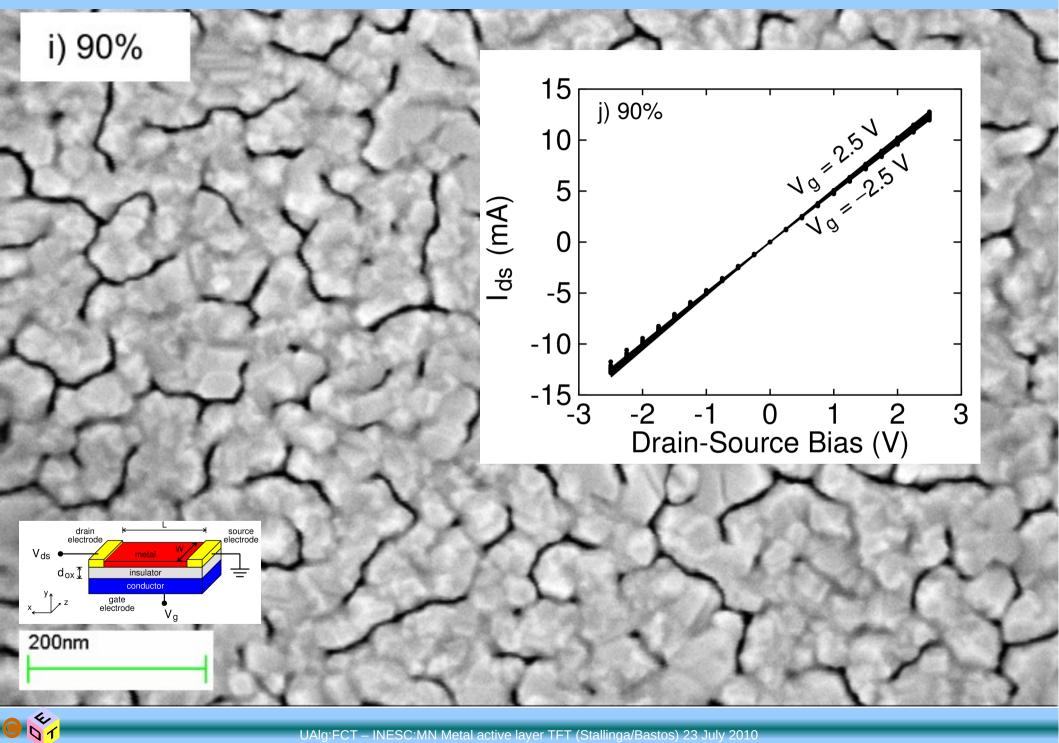
I'll show you!

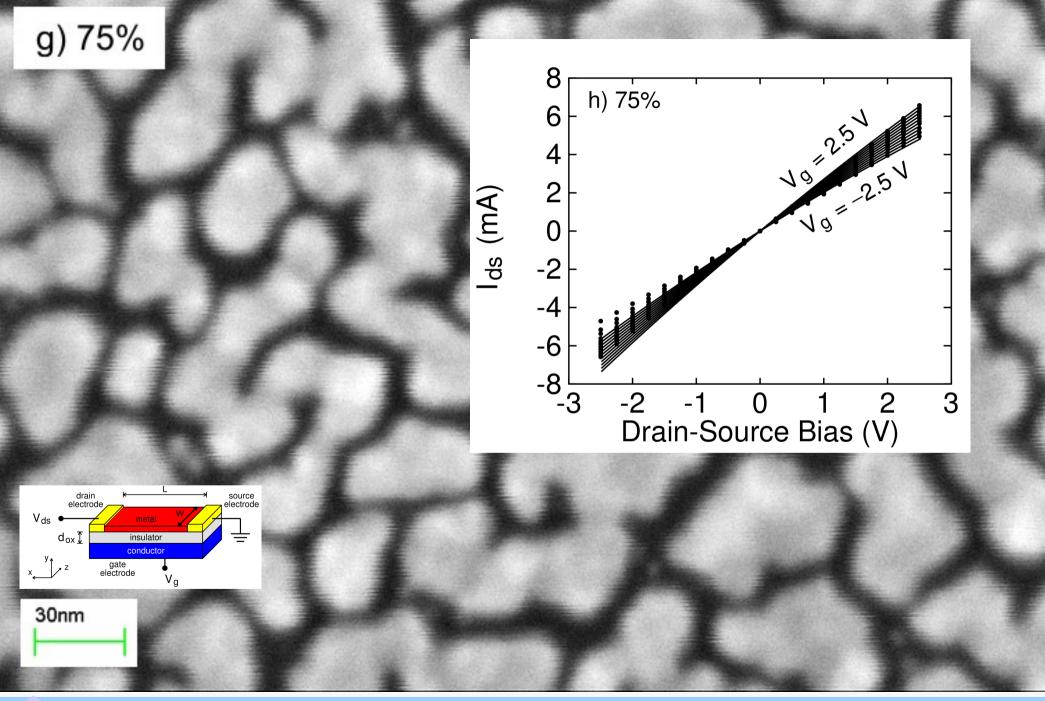




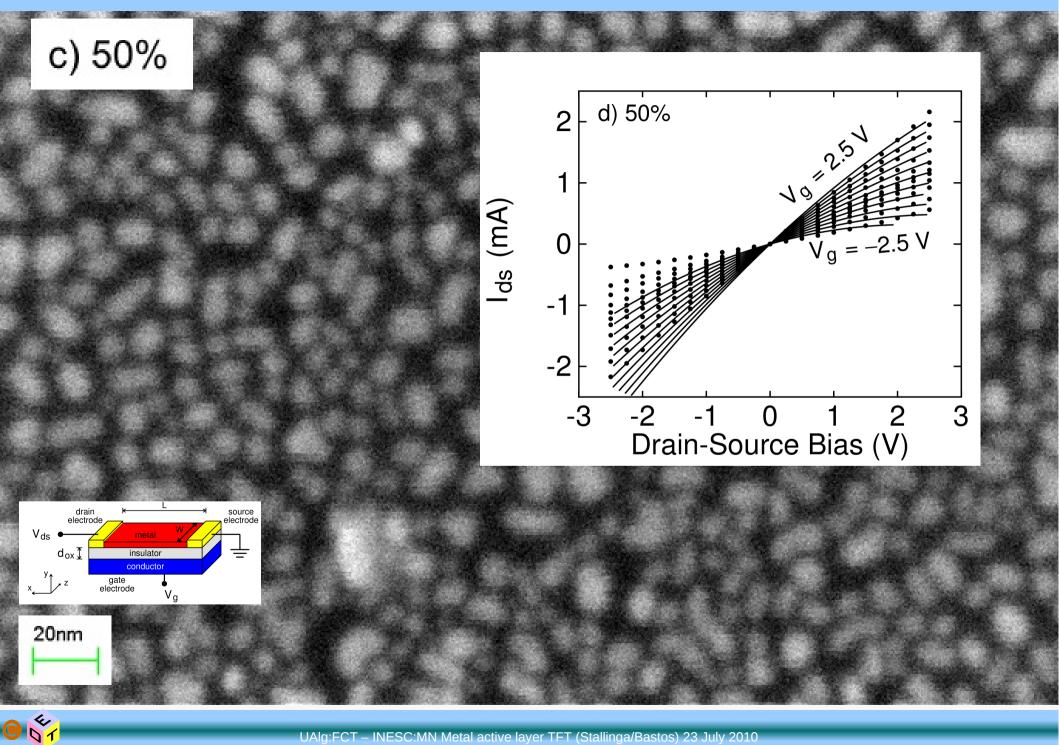


UAlg:FCT – INESC:MN Metal active layer TFT (Stallinga/Bastos) 23 July 2010

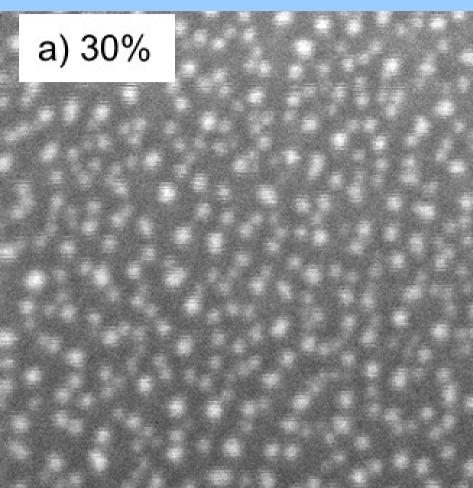


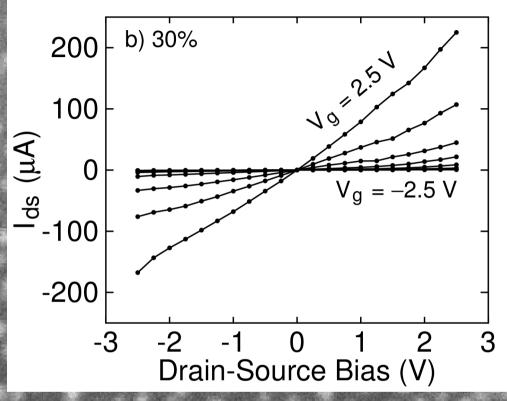


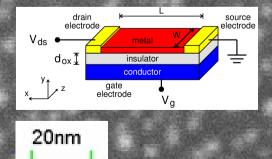
UAlg:FCT – INESC:MN Metal active layer TFT (Stallinga/Bastos) 23 July 2010



UAlg:FCT - INESC:MN Metal active layer TFT (Stallinga/Bastos) 23 July 2010



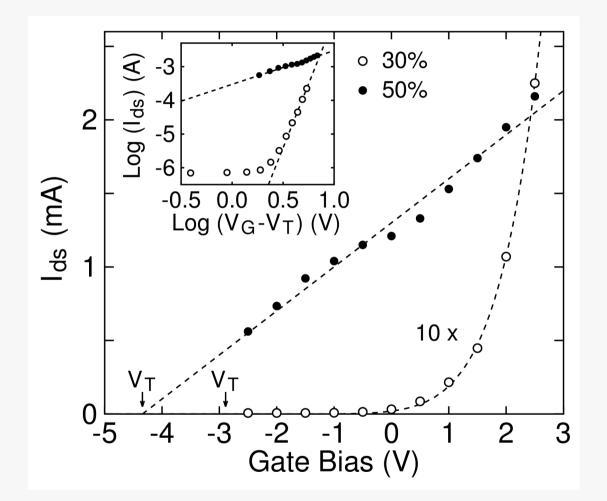






UAlg:FCT – INESC:MN Metal active layer TFT (Stallinga/Bastos) 23 July 2010

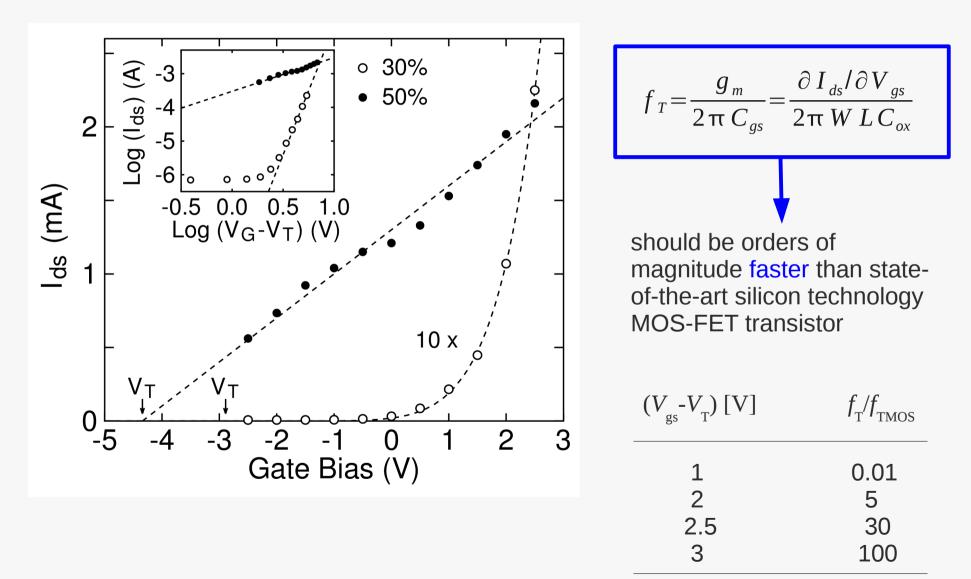
IV: Metal TFT Transfer Curves



$$I_{ds} = \mu C_{ox} (W/L) V_{DS} (V_{GS} - V_T)^{\alpha}$$



IV: Metal-layer TFT Fast electronics?



Bastos, submitted Electr. Lett. 2010